

Surface Analysis Laboratory XPS and TOF-SIMS

Never Stand Still

Mark Wainwright Analytical Centre

Solid State and Elemental Analysis Unit

Request for TOF-SIMS surface analysis (external)

Date		Company/Organisation	
Analysis requested by		Supervisor/Mgr's Name	
Contact Phone		Supervisor/Mgr's Phone	
Contact Email		Supervisor/Mgr's Email	
★ Billing Address	*	 Supervisor/Manager's Signature (authorizing charges) or date of email (email authorizing charges) 	*

Sample names and Description (detailed info should be attached separately):

1	7	
2	8	
3	9	
4	10	
5	11	
6	12	

□ Yes

□ No

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Do you need the sample returned? What analyses are required?

What analyses are required :								
	TOF-SIMS mass spectra							
	TOF-SIMS depth profile for elements or peaks of							
	Preferred sputter source		O ₂	or		Cs	or	Ar _n .
	TOF-SIMS imaging for elements or peaks of							
	TOF-SIMS 3D imaging for elements or peaks or	f						
	Anything else (please specify in a separate paper if needed)							
What furth	er sample preparation is required?							
Further comments: (eg. Special instructions, priority, importance, required by date, etc)								

SAMPLES WILL <u>NOT</u>BE KEPT. PLEASE COLLECT THEM WITHIN 4 WEEKS of ISSUE of RESULTS.

Office Use Only	Number of pu	Number of purchase order:				
Rate \$/hour	Time taken on analysis	Charge				

Laboratory Location: Room G61, Ground level, Chemical Science Building (F10), UNSW Kensington Campus Contact: Dr Bill Gong – E: b.gong@unsw.edu.au T: +61 2 9385 4694

Post Address: Mark Wainwright Analytical Centre, Room G61, Chemical Sciences Building (F10), UNSW NSW 2052, Australia Courier deliveries: MW Analytical Centre, Chemical Sciences Bldg (F10) (Enter via Gate 2-High Street), UNSW, Kensington, NSW 2052, Australia